

### **SCAN921821**

# Dual 18-Bit Serializer with Pre-emphasis, IEEE 1149.1 (JTAG), and At-Speed BIST

### **General Description**

The SCAN921821 is a dual channel 18-bit serializer featuring signal conditioning, boundary SCAN, and at-speed BIST. Each serializer block transforms an 18-bit parallel LVCMOS/LVTTL data bus into a single Bus LVDS data stream with embedded clock. This single serial data stream with embedded clock simplifies PCB design and reduces PCB cost by narrowing data paths that in turn reduce PCB size and layers. The single serial data stream also reduces cable size, the number of connectors, and eliminates clock-to-data and data-to-data skew.

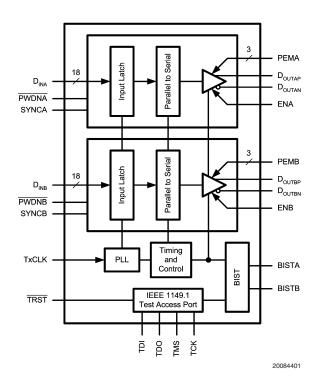
Each channel also has an 8-level selectable pre-emphasis feature that significantly extends performance over lossy interconnect. Each channel also has its own powerdown pin that saves power by reducing supply current when the channel is not being used.

The SCAN921821 also incorporates advanced testability features including IEEE 1149.1 and at-speed BIST PRBS pattern generation to facilitate verification of board and link integrity

#### **Features**

- 15-66 MHz Dual 18:1 Serializer with 2.376 Gbps total throughput
- 8-level selectable pre-emphasis on each channel drives lossy cables and backplanes
- >15kV HBM ESD protection on Bus LVDS I/O pins
- Robust BLVDS serial data transmission with embedded clock for exceptional noise immunity and low EMI
- Power saving control pin for each channel
- IEEE 1149.1 "JTAG" Compliant
- At-Speed BIST PRBS generation
- No external coding required
- Internal PLL, no external PLL components required
- Single +3.3V power supply
- Low power: 260 mW (typ) per channel at 66 MHz with PRBS-15 pattern
- Single 3.3 V supply
- Fabricated with advanced CMOS process technology
- Industrial -40 to +85°C temperature range
- Compact 100-ball FBGA package

### **Block Diagram**



## **Absolute Maximum Ratings** (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/ Distributors for availability and specifications.

Supply Voltage  $(V_{DD})$  = -0.3V to +4V

Supply Voltage (V<sub>DD</sub>)

Ramp Rate < 30 V/ms

LVCMOS/LVTTL Input

Voltage -0.3V to  $(V_{DD} + 0.3V)$ 

LVCMOS/LVTTL Output

Voltage -0.3V to  $(V_{DD} + 0.3V)$ 

Bus LVDS Driver Output

Voltage -0.3V to +3.9V

Bus LVDS Output Short

Circuit Duration 10ms
Junction Temperature +150°C

Storage Temperature -65°C to +150°C

Lead Temperature

(Soldering, 4 seconds) +220°C

Maximum Package Power Dissipation at 25°C FBGA-100 3.57 W

Derating Above 25°C 
Thermal resistance  $\theta_{JA}$   $\theta_{JC}$  
ESD Rating 
HBM, 1.5 K $\Omega$ , 100 pF 
All pins 28.57 mW/°C 
www.DataSheat  $\Omega$   $35^{\circ}\text{C/W}$   $11.1^{\circ}\text{C/W}$  28.57 mW/°C 
www.DataSheat  $\Omega$   $35^{\circ}\text{C/W}$   $35^{\circ}\text{C/W}$ 

>15 kV

>1200 V

>2 kV

## Recommended Operating Conditions

Bus LVDS pins

CDM

MM, 0Ω, 200 pF

	Min	Nom	Max	Units
Supply Voltage $(V_{DD})$	3.15	3.3	3.45	V
Operating Free Air Temperature (T <sub>A</sub> )	-40	+25	+85	°C
Clock Rate	15		66	MHz
Supply Noise			100	mV p-p

#### **DC Electrical Characteristics**

Over recommended operating supply and temperature ranges unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур	Max	Units
LVCMOS/I	VTTL Input DC Specifi	ications	•	•	•	
V <sub>IH</sub>	High Level Input Voltage		2.0		V <sub>DD</sub>	V
V <sub>IL</sub>	Low Level Input Voltage		GND		0.8	V
V <sub>CL</sub>	Input Clamp Voltage	I <sub>CL</sub> = -18 mA	-1.5	-0.7		V
I <sub>INH</sub>	High Level Input Current	$V_{IN} = V_{DD} = V_{DDMAX}$	-20	±2	+20	μΑ
I <sub>INL</sub>	Low Level Output Current	$V_{IN} = V_{SS}, V_{DD} = V_{DDMAX}$	-10	±2	+10	μА
1149.1 (JT	AG) DC Specifications					
V <sub>IH</sub>	High Level Input Voltage		2.0		V <sub>DD</sub>	V
V <sub>IL</sub>	Low Level Input Voltage		GND		0.8	V
V <sub>CL</sub>	Input Clamp Voltage	I <sub>CL</sub> = -18 mA	-1.5	-0.7		V
I <sub>INH</sub>	High Level Input Current	$V_{IN} = V_{DD} = V_{DDMAX}$	-20		+20	μΑ
I <sub>INL</sub>	Low Level Output Current	$V_{IN} = V_{SS}, V_{DD} = V_{DDMAX}$	-200		+200	μΑ
V <sub>OH</sub>	High Level Output Voltage	I <sub>OH</sub> = -9 mA	2.3		V <sub>DD</sub>	mV
$V_{OL}$	Low Level Output Voltage	I <sub>OL</sub> = 9 mA	GND		0.5	mV
I <sub>os</sub>	Output Short Circuit Current	V <sub>OUT</sub> = 0 V	-100	-80	-50	mA
	Output Tri-state	$\overline{\text{PWDN}}$ or EN = 0.8V, $V_{\text{OUT}} = 0 \text{ V}$	-10		+10	μΑ
$I_{OZ}$	Current	PWDN or EN = 0.8V, V <sub>OUT</sub> = VDD	-30		+30	μA

## DC Electrical Characteristics (Continued)

Over recommended operating supply and temperature ranges unless otherwise specified.

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Symbol	Parameter	Conditions		Min	Тур	Max	Units
	0.0.1.1.00.0						
sus LVD	S Output DC Specificati	ons	1		1	1	
$V_{OD}$	Output Differential Voltage (DO+) - (DO-)	Figure 10, $R_L = 100\Omega$		450	500	550	mV
$\Delta V_{OD}$	Output Differential Voltage Unbalance				2	15	mV
Vos	Offset Voltage			1.05	1.2	1.25	٧
$\Delta V_{OS}$	Offset Voltage Unbalance				2.7	15	mV
		Pre-Emph	nasis Level = 1	1.10	1.24	1.35	
		Pre-Emph	nasis Level = 2	1.35	1.47	1.55	
	Pre-Emphasis Output	Pre-Emphasis Level = 3		1.55	1.70	1.80	
$Q_{POV}$	Voltage Ratio	Pre-Emphasis Level = 4		1.80	1.91	1.95	
	V <sub>ODPRE</sub> / V <sub>OD</sub> I	Pre-Emphasis Level = 5		1.95	2.08	2.20	
		Pre-Emphasis Level = 6		2.10	2.21	2.35	
		Pre-Emphasis Level = 7		2.15	2.30	2.50	
los	Output Short Circuit Current	DO = 0V, Din = H, PWDN and EN = 2.4V		-10	-25	-75	mA
	TRI-STATE Output	PWDN or EN = 0.8V, DO = 0V (Note 4)           PWDN or EN = 0.8V, DO = VDD (Note 4)		-10	± 1	+10	μΑ
$I_{OZ}$	Current			-55	± 6	+55	μΑ
ower Su	pply Current (DVDD, PV	/DD and AVDD Pins)			•	•	
	Total Cumply Current		f = 66 MHz, PRBS-15 Pattern		160	225	mA
Total Supply Current  (includes load current)	$C_L = 15pF,$ $R_L = 100 \Omega$	f = 66 MHz, Worst  Case Pattern (Checker-Board  Pattern)		180		mA	
	Total Supply Current		f = 66 MHz, PRBS-15 Pattern		240		mA
I <sub>DDP</sub>	with Pre-Emphasis (includes load current)	$C_L = 15pF,$ $R_L = 100 \Omega$	f = 66 MHz, Worst  Case Pattern (Checker-Board  Pattern)		280	325	mA
I <sub>DDX</sub>	Supply Current Powerdown	PWDN = 0.8V, EN = 0.8V			1.0	3.0	mA

## **Timing Requirements for TCLK**

Over recommended operating supply and temperature ranges unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур	Max	Units
+	Transmit Clock		15.2	Т	66.7	ns
t <sub>TCP</sub>	Period		13.2	1	00.7	115
+	Transmit Clock High		0.4T	0.5T	0.6T	ns
t <sub>TCIH</sub>	Time		0.41	0.51	0.01	115
Trar	Transmit Clock Low		0.4T	0.5T	0.6T	ns
t <sub>TCIL</sub>	Time		0.41	0.51	0.01	113
+	TCLK Input			3	6	ns
t <sub>CLKT</sub>	Transition Time			3	0	115
t <sub>JIT</sub>	TCLK Input Jitter	(Note 5)			80	ps (RMS)
	•				•	•

#### **AC Electrical Characteristics**

Over recommended operating supply and temperature ranges unless otherwise specified.

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Symbol	Parameter	Conditions	Min	Тур	Max	Units
	AC Specifications			- 71	1110111	
	Bus LVDS					
t <sub>LLHT</sub>	Low-to-High		0.3	0.4	ns	
	Transition Time	Figure 2, (Note 5)				
	Bus LVDS	$R_L = 100\Omega$ ,				
t <sub>LHLT</sub>	High-to-Low	C <sub>L</sub> =10pF to GND		0.3	0.4	ns
	Transition Time					
+	DIN (0-17) Setup to	Figure 4 (Note F)	1.9			ne
t <sub>DIS</sub>	TCLK	Figure 4, (Note 5) $R_{L} = 100\Omega,$	1.9			ns
t <sub>DIH</sub>	DIN (0-17) Hold from	$C_L = 10032$ , $C_L = 10$ F to GND	0.6			ns
— ЧОН	TCLK	CL=TOPT to GITE	0.0			
t <sub>HZD</sub>	DO ± HIGH to			3.9	10	ns
	TRI-STATE Delay					
t <sub>LZD</sub>	DO ± LOW to	Figure 5		3.5	10	ns
	TRI-STATE Delay	$R_1 = 100\Omega$ ,				
t <sub>zhD</sub>	DO ± TRI-STATE to	C <sub>L</sub> =10pF to GND		3.2	10	ns
	DO ± TRI-STATE to					
t <sub>ZLD</sub>			2.4	10	ns	
	LOW Delay					
t <sub>SPW</sub>	SYNC Pulse Width	Figure 7,	5*t <sub>TCP</sub>		6*t <sub>TCP</sub>	ns
	$R_{L} = 100\Omega$ Serializer PLL Lock Figure 6,					
t <sub>PLD</sub>	Time	Figure 6, $R_L = 100\Omega$	510*t <sub>TCP</sub>		1024*t <sub>TCP</sub>	ns
	Serializer Delay	Figure 8, $R_L = 100\Omega$	t + 2.5	t <sub>TCP</sub> + 4.5	t + 6.5	ns
t <sub>SD</sub>	Channel to Channel	1 igaic 0 , 11 = 100s2	TCP + 2.5	TCP + 4.0	TCP + 0.0	110
t <sub>skcc</sub>	Skew			70		ps
		Room Temperature, V <sub>DD</sub> = 3.3V,				ps
t <sub>RJIT</sub>	Random Jitter	66 MHz		6.1		(RMS)
	Deterministic Jitter	15 MHz	-390		320	ps
t <sub>DJIT</sub>	Figure 9, (Note 5)	66 MHz	-60		30	ps
1149.1 (JT	AG) AC Specification					<u> </u>
	Maximum TCK Clock					
f <sub>MAX</sub>	Frequency		25			MHz
	TDI or TMS Setup to		0.4			
t <sub>S</sub>	TCK, H or L		2.4			ns
	TDI or TMS Hold	C <sub>L</sub> = 15pF,	0.0			
t <sub>H</sub>	from TCK, H or L		2.8			ns
_	TCK Pulse Width, H	$R_L = 500 \Omega$	10			ne
t <sub>W1</sub>	or L		10			ns
t <sub>W2</sub>	TRST Pulse Width, L		10			ns
tees	Recovery Time,		2			ns
t <sub>REC</sub>	TRST to TCK		_			110

Note 1: "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. They are not meant to imply that the devices should be operated at these limits. The table of "Electrical Characteristics" specifies conditions of device operation.

**Note 2:** Typical values are given for  $V_{CC} = 3.3V$  and  $T_A = +25^{\circ}C$ .

Note 3: Current into device pins is defined as positive. Current out of device pins is defined as negative. Voltages are referenced to ground except VOD,  $\Delta$ VOD, VTH and VTL which are differential voltages.

 $<sup>\</sup>textbf{Note 4:} \quad I_{OZ} \text{ is measured at each pin. The DOUT pin not under test is floated to isolate the TRI-STATE current flow.}$ 

Note 5: Guaranteed by Design (GBD) using statistical analysis.

## **AC Timing Diagrams and Test Circuits**

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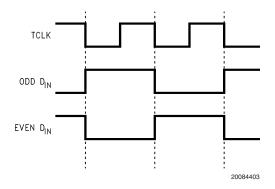


FIGURE 1. "Worst Case" Serializer IDD Test Pattern

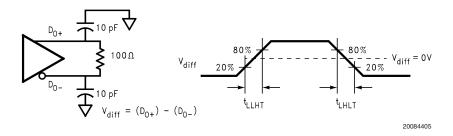


FIGURE 2. Serializer Bus LVDS Distributed Output Load and Transition Times

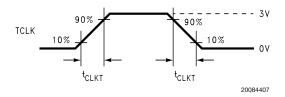


FIGURE 3. Serializer Input Clock Transition Time

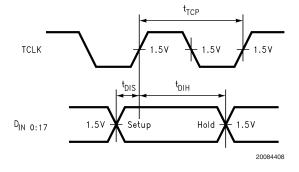
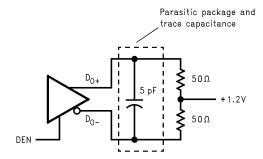


FIGURE 4. Serializer Setup/Hold Times

## AC Timing Diagrams and Test Circuits (Continued)

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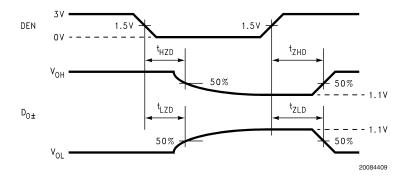


FIGURE 5. Serializer TRI-STATE Test Circuit and Timing

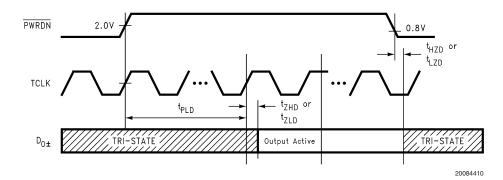


FIGURE 6. Serializer PLL Lock Time, and PWRDN TRI-STATE Delays

## AC Timing Diagrams and Test Circuits (Continued)

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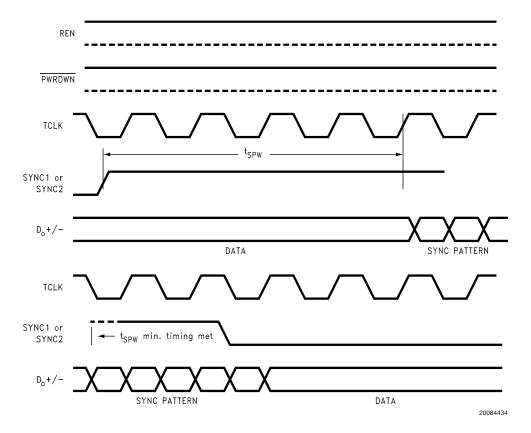


FIGURE 7. SYNC Timing Delay

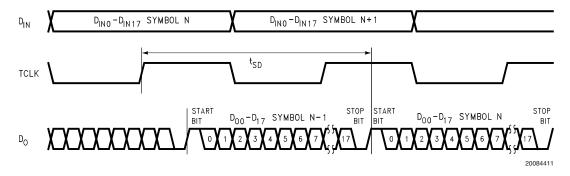


FIGURE 8. Serializer Delay

## AC Timing Diagrams and Test Circuits (Continued)

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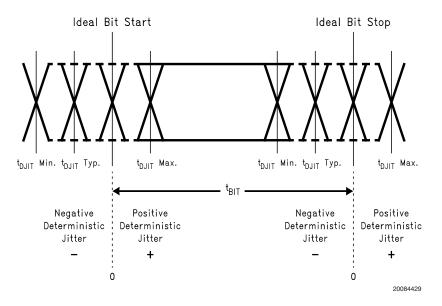
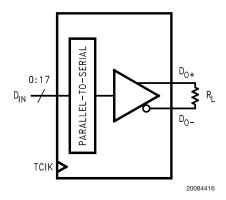


FIGURE 9. Deterministic Jitter and Ideal Bit Position



 $\mathsf{V}_\mathsf{OD} = (\mathsf{DO}^+) - (\mathsf{DO}^-).$ 

Differential output signal is shown as (DO+)-(DO-), device in Data Transfer mode.

FIGURE 10.  $V_{\rm OD}$  Diagram

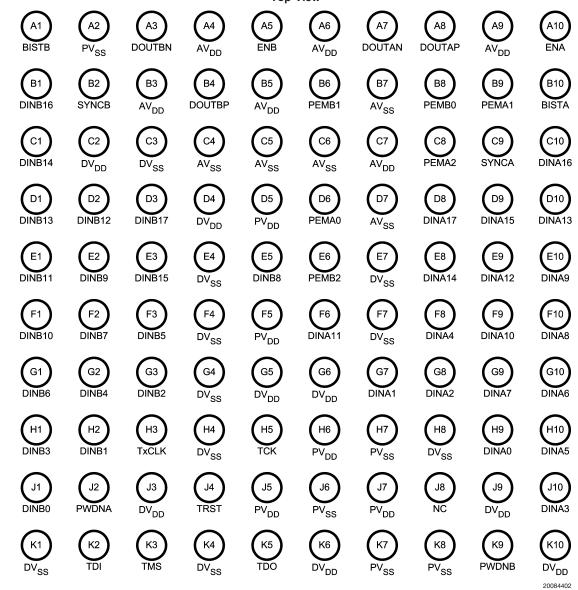
## **Pre-emphasis Truth Table**

PEM LEVEL	PEM2	PEM1	PEM0
0	L	L	L
1	L	L	Н
2	L	Н	L
3	L	Н	Н
4	Н	L	L
5	Н	L	Н
6	Н	Н	L
7	Н	Н	Н

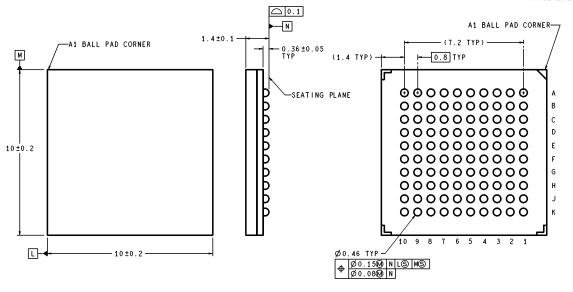
## Pin Diagram

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#### SCAN921821TVV Top View



#### **Pin Descriptions** www.DataSheet4U.com Pin Name Pin Count I/O, Type Description **DATA PINS** DINA0-17 18 Transmitter inputs. There is a pull-down circuitry on each of these pins which are I, LVCMOS active if respective PWDNA or PWDNB pin is pulled high. **DINB0-17** 18 **DOUTAP** 1 **DOUTAN** 1 O,BLVDS Inverting and non-inverting differential transmitter outputs. **DOUTBP** 1 **DOUTAN** 1 **TIMING AND CONTROL PINS** Transmitter reference clock. Used to strobe data at the inputs and to drive the **TxCLK** 1 I. LVCMOS transmitter PLL. There is a pull-up circuitry on this pin which is always active. Transmitter outputs enable pins. There is a pull-down circuitry on each of these **ENA** 1 pins that are active if corresponding PWDNA or PWDNB pin is pulled high. I, LVCMOS When these pins are set to LOW, the transmitter outputs will be disabled. The **ENB** 1 PLL will remain locked. Stand-by mode pins. There is a pull-down circuitry on each of these pins that are **PWDNA** 1 I, LVCMOS always active. When these pins are set to LOW, the transmitter will be put in low **PWDNB** 1 power mode and the PLL will lose lock. Transmitter synchronization pins. There is a pull-down circuitry on each of these **SYNCA** 1 pins that are active if corresponding PWDNA or PWDNB pin is pulled high. I, LVCMOS When these pins are set to HIGH, the transmitter will ignore incoming data and **SYNCB** 1 send SYNC patterns to provide a locking reference to receiver(s). **PRE-EMPHASIS PINS** PEMA0-2 8-level pre-emphasis selection pins. There is a pull-down circuitry on each of these pins which are active if corresponding $\overline{\text{PWDNA}}$ or $\overline{\text{PWDNB}}$ pin is pulled I, LVCMOS PEMB0-2 3 **JTAG PINS** TDI 1 I, LVCMOS Test Data Input to support IEEE 1149.1. There is a pull-up circuitry on this pin which is always active. TDO Test Data Output to support IEEE 1149.1. 1 O, LVCMOS TMS 1 I, LVCMOS Test Mode Select Input to support IEEE 1149.1. There is a pull-up circuitry on this pin which is always active. TCK 1 I, LVCMOS Test Clock Input to support IEEE 1149.1. There is no failsafe circuitry on this pin. **TRST** 1 I. LVCMOS Test Reset Input to support IEEE 1149.1. There is a pull-up circuitry on this pin which is always active. **BIST PINS BISTA** 1 I, LVCMOS BIST selection pins. These pins select which transmitter will generate a PRBS like data. There is a pull-down circuitry on these pins which are active if **BISTB** 1 corresponding PWDNA or PWDNB pin is pulled high. **POWER PINS** AVDD 6 I, POWER Power Supply for the LVDS circuitry. DVDD 8 I, POWER Power Supply for the digital circuitry. **PVDD** 5 Power Supply for the PLL and BG circuitry. I, POWER I, POWER **AVSS** 5 Ground reference for the LVDS circuitry. DVSS 10 I, POWER Ground reference for the digital circuitry. **PVSS** 5 I, POWER Ground reference for the PLL and BG circuitry. **OTHER PINS** NC 1 N/A Not connected.



DIMENSIONS ARE IN MILLIMETERS

SLC100A (Rev B)

Dimensions shown in millimeters only Order Number SCAN921821TSM **NS Package Number SLC100A** 

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IEEE 1149.1 (JTAG), and At-Speed BIST